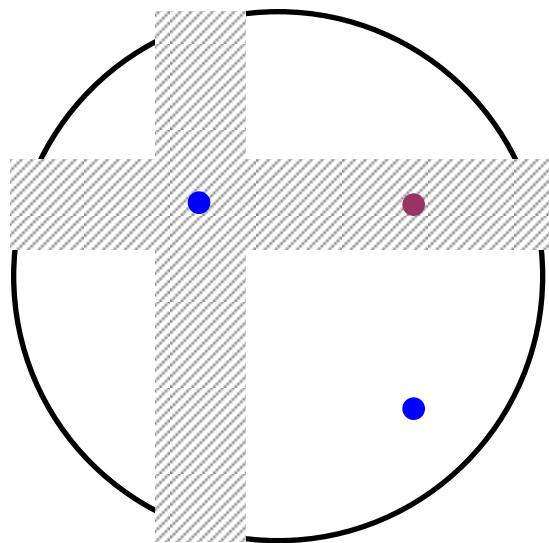
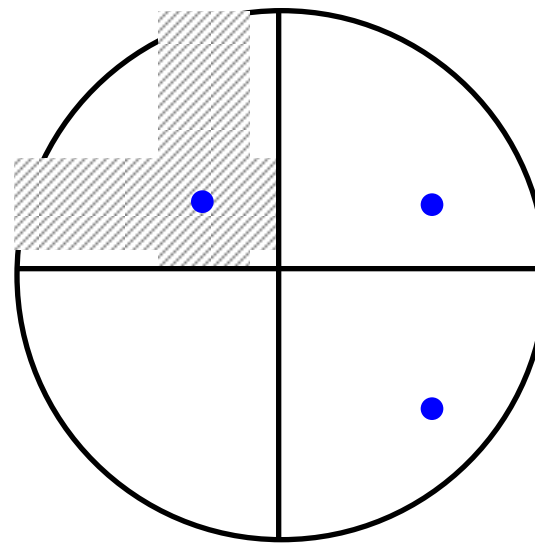






Multihit problem, dead-time and segmented DLD behavior



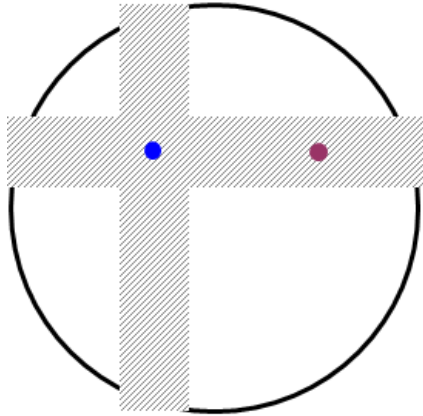
DLD with
single anode



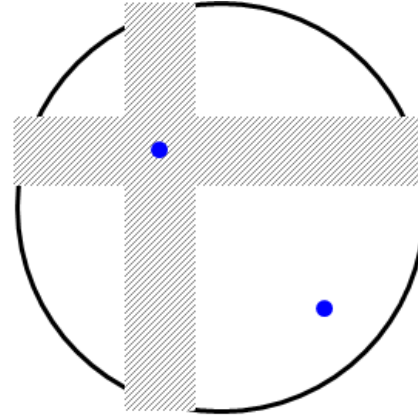
DLD with
segmented anode

- 

active DLD area (segmented, not segmented)
- 
dead area for double hit recognition in time
- 
event

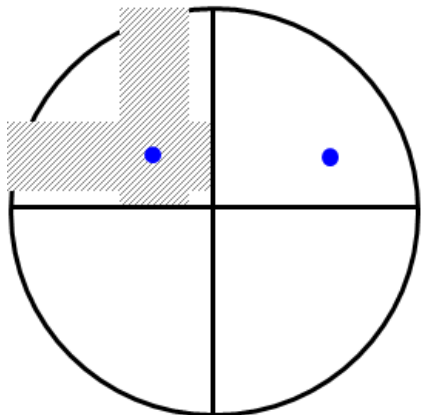
Multihit problem, dead-time and segmented DLD behavior



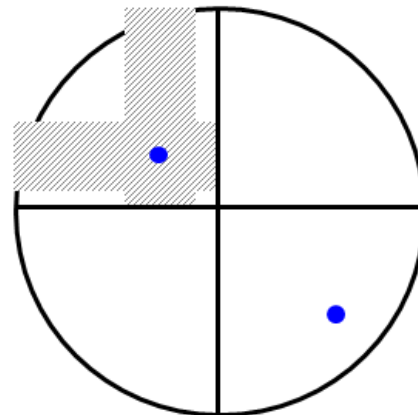
not detectable



detectable



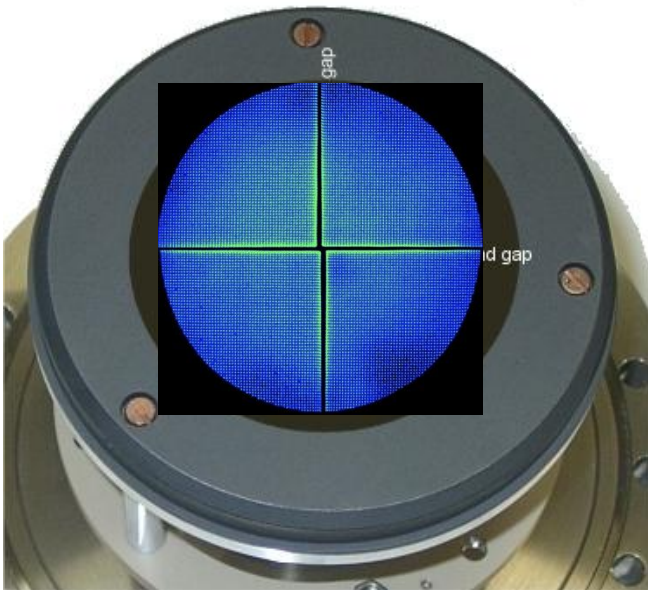
detectable



detectable

Special 4 Quadrant DLD layouts

3D-DLD4040-4Q (80 mm diameter) and 3D-DLD3030-4Q (60 mm diameter):
4 fold segmented DLD using 4 independent DLD readout systems in parallel
each segment has low dead times (15 ns DLD4040-4Q / 9 ns DLD3030-4Q)



- Multi-hit 2D/3D 4-fold delayline detector
- Up to 4 multi hits with absolutely zero dead time
- Up to 400 multi hits per 1 μ s
- Burst rates above 100 MCPS equivalent
- 60 x 60 mm² (or 80 x 80 mm²) active area of DLD body and \varnothing 80 mm active MCP area
- Down to 30 μ m of pixel size
- < 250 ps over all time resolution
- Linear response due to single event counting
- Extremely low dark count rate: ≤ 0.2 cps/ cm²
- Up to 40 MCPS random hit rate in 2D/3D mode

Special 4 Quadrant DLD layouts

3D-DLD4040-4Q:

grid mask measurement with 0.7 mm pitch and 0.2 mm holes

